

## Derivation: Polarization Figure-of-Merit

R. Jones

11/4/04

- \* Suppose that I have some signal in a region of final-state phase space  $\delta\hat{\Omega} = dt d\hat{M}$  where  $\hat{M}$  represents mass and angle variables internal to the mesonic final state  $X$  in  $\vec{r}_p \rightarrow Xb$  ( $b$  is any final-state baryon)
- \* Let the variable  $\phi$  represent the plane of  $\vec{E}$  of the photon in the  $G$ - $J$  frame,  $\phi \in [-\pi, \pi]$ .
- \* Then, events in  $\delta\hat{\Omega}$  have a general  $\phi$  distribution

$$f(\phi) = 1 + P(a \cos 2\phi + b \sin 2\phi)$$

where  $a$  and  $b$  measure the relative contributions from natural/unnatural exchanges. Given a sample of size  $N$ , how does the statistical error on extracted values for  $a, b$  depend on  $P$ ?

I use a maximum likelihood estimator:

$$\ln \mathcal{L} = \sum_{i=1}^N \ln f(\phi_i)$$

$$\text{solution: } \frac{\partial \ln \mathcal{L}}{\partial a} = \sum_{i=1}^N \frac{P \cos 2\phi_i}{f(\phi_i)} = \frac{\partial \ln \mathcal{L}}{\partial b} = \sum_{i=1}^N \frac{P \sin 2\phi_i}{f(\phi_i)} = 0$$

These 2 equations can be linearized and solved by iteration in the usual way (see standard refs. on the M.L. method).

\* Errors on M.L. estimators:  $\hat{a}, \hat{b}$

In the large  $N$  limit,  $\ln \mathcal{L}$  can be expanded as a parabolic form around the maximum, and the curvature gives the error inverse matrix.

$$\frac{\partial^2}{\partial a^2} \ln \mathcal{L} = - \sum_{i=1}^N \frac{P^2 \cos^2 2\phi_i}{f^2(\phi_i)} \sim - \frac{1}{\sigma_a^2}$$

There is a  $P$ -dependence in the denominator  $f^2$ , but the dominant behavior goes as the canonical form

$$\sigma_a^2 \propto \underbrace{(P^2 N)}^{-1}$$

• figure of merit.

That is, errors on parameter  $a$  go like  $\frac{1}{P\sqrt{N}}$ .

If that is what people mean by "linear in  $P$ " then we are in agreement with that. Traditional figure-of-merit is scaled to be linear in beam time, which gives a feeling for how much savings in operations are obtained with a given improvement in beam properties.